

Search Notes

Application/Control No.

10/629,301

Examiner

Hanh Phan

Applicant(s)/Patent under
Reexamination

ARONSON ET AL.

Art Unit

2613

SEARCHED

Class	Subclass	Date	Examiner
398	135	68/62107	HP
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INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
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